Auger Electron Spectroscopy (AES)

Technical Parameters

Auger Electron Spectrometer: Physical Electronics PHI 670 Nanoprobe

Ion source: Ar⁺ Ions (Energy 1-5 keV)

Primary Beam: focused electron beam (1 - 25 keV) – Field emitter
Signal Detected: Auger electrons, Secondary electrons

Elements Detected: Li-U; Chemical bonding information

Lateral Resolution: 100 nm
Depth Resolution: 2 – 3 nm (Profiling mode)
Detection Limits: 0.1-1 at% sub-monolayer

Application areas

- Surface analysis
- Particle analysis
- Small-area depth profiling
- Defect analysis
- Thin film composition analysis

Contact person

Dr. Ioan Costina
Phone: +49 335 5625 370
Fax: +49 335 5625 327
Email: costina@ihp-microelectronics.com